

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/630,347	INLOW, MARK C.
	<b>Examiner</b> Tai T. Nguyen	<b>Art Unit</b> 2612

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
SEARCH AS ABOVE		10/1/2007	TN